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ABSTRACT

An improved, self-contained gas injection system for the Divertor Material Evaluation System (DiMES) on DIII-D has been employed for *in-situ* study of chemical erosion in the tokamak divertor environment. The Mark II porous plug injector (PPI) releases methane through a porous graphite surface into the divertor plasma at the outer strike point at a rate precisely controlled by a micro-orifice flow restrictor. This method minimizes perturbation to local plasma while simulating the immediate environment of methane molecules released from a solid graphite surface. The methane flow rate was the same order of magnitude as that predicted for intrinsic chemical sputtering. Effective photon efficiencies resulting from CH_4 are reported and the contribution of chemical versus physical sputtering to the source of C^+ at the target is assessed through simultaneous measurement of CII line, and CD plus CH band emissions during release of CH_4 from the PPI, compared with that seen in intrinsic sputtering.

I. INTRODUCTION

Since chemical sputtering plays a key role in tritium co-deposition, target lifetime, and flake and dust formation, characterizing it in present day fusion devices is crucial for the successful operation of ITER [1]. In order to relate measured photon fluxes from chemical sputtering (CS) to particle fluxes at the measurement location, inverse photon efficiencies, i.e., dissociations (D) per detected photon [excitation (X) * branching ratio (B)], or D/XB values) must be derived for gases released by CS, usually by gas puffing experiments. The porous plug injector (PPI) was built for the DIII-D Divertor Materials Interaction (DiMES) system as an *in-situ* diagnostic to admit methane (or another hydrocarbon) through a porous graphite surface, such that its interaction with plasma and surface closely approximates a hydrocarbon molecule released from a carbon surface by CS. CH₄ is used for PPI injections as a proxy for C_xD_y released by CS in order to take advantage of the 0.5 nm separation of bandheads between CH and CD near 430 nm. Injecting methane at a known and controlled rate provides direct comparison to intrinsic emission levels for calibration of spectroscopic signals. The porous surface is designed such that the size and spacing of the holes is on the order of the mean free path of CH₄ in the divertor plasma. The injection rate selected corresponds to a 2% intrinsic D → C erosion yield, $Y_{\text{chem}}^{\text{C}}$, with $\Gamma_{\text{D}^+} \approx 3 \times 10^{18} / \text{cm}^2\text{s}$ [2], thus providing $\sim 4 \times 10^{17}$ CH₄ molecules/s (0.013 TorrL/s, ~ 1 sccm) over the holed area of the PPI cap at the outer strike point (OSP). Emissions in excess of intrinsic background from the region above and around the PPI in the lower divertor floor are studied in typical attached and semi-detached operating regimes in DIII-D, and effective D/XB values calculated for those conditions.

II. EXPERIMENT AND OBSERVATIONS

This experiment is based on a previous one at DIII-D [3], but with significant improvements in gas flow control, and diagnostic coverage. The PPI is composed of a DiMES sample inserted flush to the lower divertor floor (within 1 mm), and a self-contained gas delivery system enclosed within the DiMES hydraulic arm assembly. Instead of a programmable valve which led to gas flow rates typically $\sim 5\text{--}10\times$ higher than desired in the previous experiment, the Mark II PPI incorporates a demountable micro-orifice flow restrictor ($4.14\ \mu\text{m}$ diameter) and a high pressure canister. The micro-orifice ensured that gas leaked out at a predictable and controlled rate over the course of an experimental day. New and improved diagnostic capabilities were also available for the 2007 PPI experiment. These included a new camera and optics for the multichord divertor spectrometer (MDS) which monitors emission from the PPI on a 2.1 cm diameter view-chord view-chord (the on-DiMES chord), and intrinsic emission from the graphite surface on a toroidally displaced view-chord (the off-DiMES chord). The MDS system sensitivity viewing the 430 nm region was improved by a factor of ~ 100 compared to 2005. A new DiMES TV camera was also installed for monitoring 2-D spectral emission in the DiMES region on the lower divertor floor (Fig. 1).

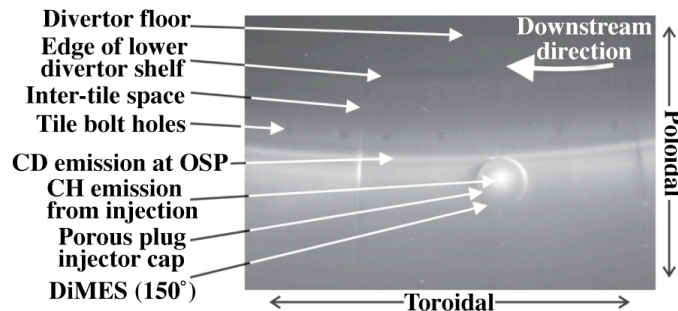


Fig. 1. Image from DiMES TV using the CD and CH filter (centre: 430.5 nm, bandpass: 3.5 nm), showing emission from the OSP and SOL, and that from the PPI above the intrinsic background.

An L-mode deuterium plasma with a lower single-null (LSN) shape was developed with parameters of $I_p = 1.1$ MA, $B = 2.0$ T, $P_{\text{NBI}} \sim 0.23$ MW, $\langle n_e \rangle \sim 2.5 \times 10^{19} \text{ m}^{-3}$ in attachment and $\langle n_e \rangle \sim 5.0 \times 10^{19} \text{ m}^{-3}$ in detachment. Shots were run with the OSP (width ~ 1 cm) swept over divertor shelf and held steady at the inboard edge of the DiMES port ($1.462 < R_{\text{DiMES}} < 1.510$ m). Langmuir probes, and divertor Thomson scattering (DTS) provided plasma parameters, and filterscopes provided additional data on hydrogenic and intrinsic impurities near the target. OSP plasma parameters were as follows: In attachment, $\Gamma_{\text{D}^+, \text{att}}^{\parallel} \sim 3.0 \times 10^{18} / \text{cm}^2 / \text{s}$, $n_e \sim 1.5 \times 10^{13} / \text{cm}^3$ and $T_e \sim 25$ eV, and in detachment, $\Gamma_{\text{D}^+, \text{det}}^{\parallel} \sim 6.5 \times 10^{18} / \text{cm}^2 / \text{s}$,

$n_e \sim 6.0 \times 10^{13} / \text{cm}^3$ and $T_e \sim 2 - 3$ eV. The ratio of D_β / D_α emission from attached to detached operation was found to rise from ~ 0.1 to ~ 0.2 , while integrated D_γ emission, ϕ_{D_γ} , rose by $\sim 20 \times$, confirming a low divertor temperature, but indicating very weak degree of detachment.

Sample spectra from the MDS ($\Delta\lambda = 0.00765$ nm, $\lambda/d\lambda = 56,300$, 7.8 nm spectral range, 200–250 ms integration time) are shown in Fig. 2 for attached plasma conditions. Spectrally integrated emission from the gas puff (i.e., incremental emission over the intrinsic signal, due to the puff only) is determined by subtracting the signal off-DiMES from the signal on-DiMES. Emission from the puff is found to be approximately equal in strength to that from intrinsic sputtering in both plasma conditions. Integrated puff-only CD plus CH emission, $\phi_{\text{CD+CH}}^{\text{puff-only}}$, versus PPI flow rate shows a highly linear relationship over the puffing rates in both attached and detached plasmas, indicating that perturbation to the local plasma was minimized. The intensity of H_γ (434.2 nm) as a consequence of the PPI puff was found to be equivalent to $\sim 2\% - 3\%$ of the local D_γ (433.9 nm) emission at the DiMES location, indicating the puff had a minimal impact on local hydrogenic recycling. Boron is a significant impurity in DIII-D due to the boronization (BZN) process used for wall conditioning. The boron deuteride (BD) A-X band emits in the 430 nm region [4]; the p-branch overlaps the CD and CH A-X band in the 427–432 nm region, while the q-branch is more isolated from CD and CH in the region of 432.5–432.8 nm. Through correlation of the integrated intensity of each BD branch immediately following a BZN on DIII-D when CD emission was minimal, the contamination of CD and CH in the 427.0–431.5 nm region by the BD band was determined and corrected for in PPI data.

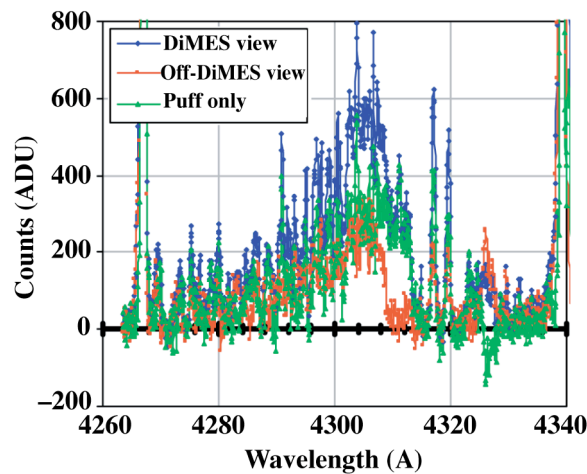


Fig. 2. Spectral profiles of the CD- and CH-band plasma from the MDS diagnostic in attached divertor plasma, showing the emission at the PPI (blue), the intrinsic emission away from the PPI (green), and the difference due to the puff alone (red). Similar profiles are found in detached conditions.

III. DISCUSSION

The effective D/XB for CH includes consideration for all breakup, prompt deposition, and re-erosion processes that ‘pass through’ the CH molecular fragment. For CH and CD, a full account of emission in the A-X Gerö band is made using a ‘full span’ expansion factor [5], $f_{A-X}^{\text{CH or CD}}(T_{\text{rot}}, \lambda_{\text{span}}) = 1.8$, $\lambda_{\text{span}} = 427.0 - 431.5$ nm. The effective D/XB values for CH are calculated as

$$\left[\frac{D}{XB} \right]_{A^2\Delta \rightarrow X^2\Pi}^{\text{CH}_4 \rightarrow \text{CH}} = \frac{\Gamma^{\text{CH}_4}}{\phi_{A^2\Delta \rightarrow X^2\Pi}^{\text{CH}_4 \rightarrow \text{CH}} \cdot f_{A-X}^{\text{CH}}(T_{\text{rot}}, \lambda_{\text{span}})}, \quad (1)$$

and equal to 11.8 ± 1.5 in attachment, 24.0 ± 2.0 in detachment. These values are considerably lower than those derived in the 2005 experiment. They are, however, in general agreement with the only other data which is taken at an injection rate on the order of the intrinsic CS rate [4] in which $\Gamma^{\text{CD}_4} = 5 \times 10^{17}$ /s were injected from an inlet extended into the SOL. The observation that the current values and those of Ref. [4] are so far outside the error bars for previous measurements may be because processes involved at injection rates equal to intrinsic CS rates differ from those at the higher ($\geq 10 \times$ intrinsic) rates which were used for all other measurements reported, including those of the 2005 PPI experiment. The inverse photon efficiency for CH is found to increase by a factor of ~ 2 from attachment to detachment which is in agreement with observations made in the 2005 experiment and other data previously reported [3].

The average chemical erosion yield over the MDS view chord at the OSP may be deduced by comparison of the integrated emission from intrinsic sources with that from the PPI for a known injection rate, by the relation

$$Y_{\text{chem}}^{\text{C}} = \frac{\Gamma_{\text{CH}_4}}{\Gamma_{\text{D}^+}} \cdot \frac{\phi_{\text{CD}}^{\text{Intrinsic}}}{\phi_{\text{CH}}^{\text{PPI puff}}}, \quad (2)$$

where Γ_{D^+} is the perpendicular ion flux over the holed region of the PPI as measured by the Langmuir probes. In attached conditions, a yield of $\sim 2.6\%$ is found which is in agreement with laboratory measurements [6], but significantly higher than previous inferred measurements on DIII-D [7]. The lack of agreement to previous experiments may have been due to a high detection threshold for the MDS system. In detachment, a yield of $\sim 1.7\%$ is found, accounting for ionized hydrogenic flux alone (i.e., no accounting for neutral hydrogenic flux). While this value is approximately that expected from laboratory measurements (for $\text{D}^+ = 10$ eV $Y_{\text{chem}}^{\text{C}, 300 \text{ K}} \approx 0.7 \pm 0.2\%$, and $Y_{\text{chem}}^{\text{C}, 500 \text{ K}} \approx 1.7 \pm 0.2\%$ [8]), the CS yield in detachment is not found to decline drastically as has been inferred previously on DIII-D. This former observation in detachment, however, may be because only a semi-detached state was achieved at the OSP.

Production efficiencies, described in Ref. [3], for CH from injection of CH₄ into attached divertor conditions are found to be $\eta_{\text{CH}_4 \rightarrow \text{CH, att}} = \Gamma_{\text{CH}} / \Gamma_{\text{CH}_4} = 0.75 \pm 0.1$, and from injection of CH₄ into detached divertor conditions, $\eta_{\text{CH}_4 \rightarrow \text{CH, det}} = \Gamma_{\text{CH}} / \Gamma_{\text{CH}_4} = 0.08 \pm 0.01$. These values are higher than those measured in the 2005 PPI experiment with a 10× higher gas puff rate, possibly due to self-shielding of CH₄ from the local plasma in the previous experiment which would lead to lower interaction than occurs at intrinsic levels. This difference highlights the necessity for the C injection rate in the puff to be on the order of the intrinsic C-release rate due to CS.

For these experiments, the PPI gas puff imitates a source of purely chemically eroded carbon, and thus the resulting ratio of CII to CH and CD emission for the puff can be considered indicative of the intrinsic CS source. The ratio of the spectrally integrated CD and CH band brightness (427.0-431.5 nm) to that of the nearby CII line (426.7 nm) provides, in principle, a direct method for determining the relative contribution to the C⁺ source by CS versus that of other sources, primarily physical sputtering. In Fig. 3, the relationship between ϕ_{CII} (426.6-426.85 nm) and ϕ_{CD} (427–431 nm, with BD-band correction) is shown for intrinsic sources at the OSP, and found to be nearly 1:1 and linear. Spectrally integrated data for the puff alone is shown in Fig. 4 and also found to be linear, further indicating that the puff was non-perturbative to the local plasma. These data demonstrate that the magnitude of integrated CD and CH from the puff is approximately equal to that of the intrinsic data, indicating that the puff was effective at replicating CD emission from intrinsic chemical erosion. The slope of the linear fit to the puff-only data in attached plasma, Fig. 4(a), is ~80% of that for the intrinsic emission leading to the conclusion that sources of C⁺ produced by CS are dominant in attached divertor conditions. This conclusion, while in general agreement with observations made for C⁰ sources based on the CI line profile [9], is contrary to PPI data analyzed at CI (910 nm), and CII (514 and 658 nm) where a C⁰/C⁺ contribution from CS of 10%–20% is measured. Also, the implication that CS contributes 4X more to C⁺ than other sources including physical sputtering (PS) (i.e., 80% from CS, then 20% from PS) may lead to an inferred absolute C⁺ source that is potentially much more than that measured. These data are the focus of ongoing study and modelling using a 3-D version of the DIVIMP-HC Monte Carlo code by Y. Mu [10]. Figure 4(b) shows the puff-only data in detachment where the puff contributes very little to measured CII emission, and is therefore inferred to be a minor, ~10%, contributor to local C⁺ at the OSP. Intrinsic CII in detachment may be primarily from recombination of carbon in higher charge states transported from the scrape-off layer (SOL). Emission of CH and CD in detachment does not extinguish as previously observed at the OSP with $T_e < 1$ eV [7]. When DiMES is recessed and a blank hole left in the attached divertor surface, reductions of 15%–20% in the CII emission and 30%–55% of the CD emission are found compared with the intrinsic emission with a graphite surface present. In detached divertor conditions, reductions of 25%–30% of the intrinsic CII emission and ~ 50% of the intrinsic CD emission are found.

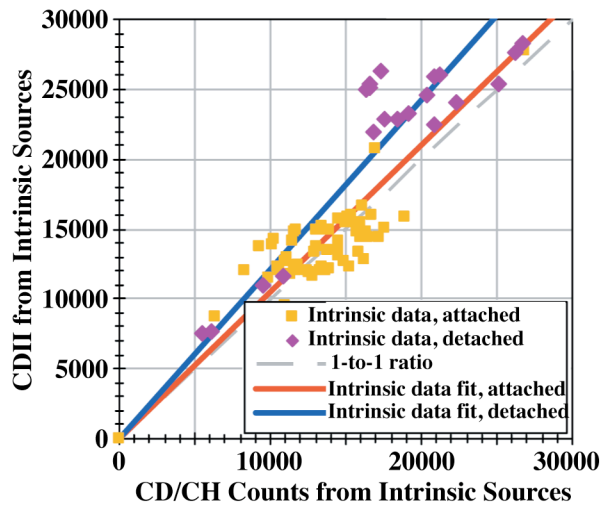


Fig. 3. Spectrally integrated emission of CII line (426.7 nm) versus CD band (427–431 nm) is shown for the intrinsic chemical sputtering source near the OSP in shots with attached and semi-detached divertor conditions. Data in both cases are found to be well fit by a linear relationship with a slope near 1.

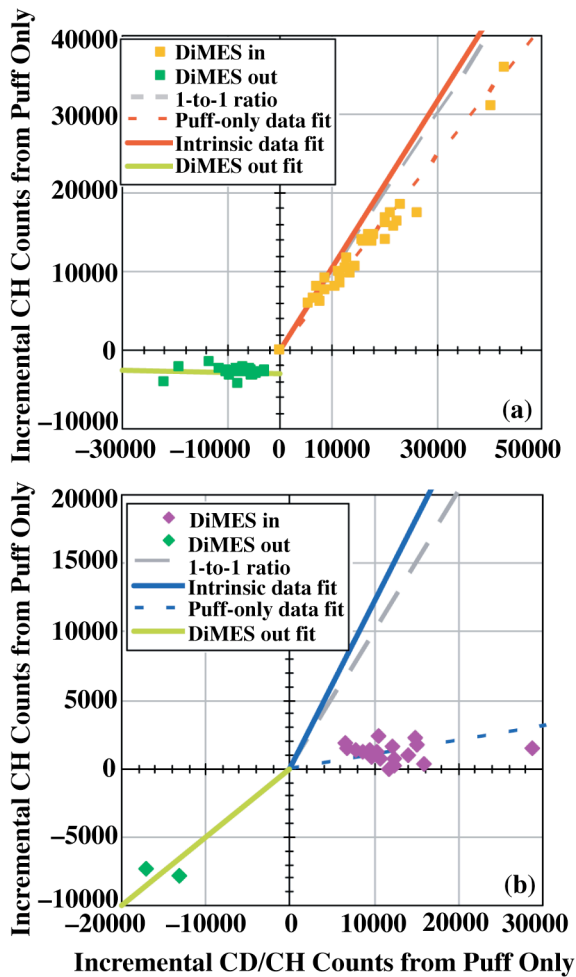


Fig. 4. Incremental integrated CII versus CD and CH for emission from the PPI gas puff only in shots with (a) an attached divertor, and (b) a semi-detached divertor. In attachment, data from the puff alone is fit to a linear slope of ~ 0.8 . In detachment, incremental integrated CD and CH is found to be larger than that of CII by a factor of $\sim 10:1$, indicating that CS is a minor contributor to C^+ near the OSP in detachment.

IV. CONCLUSIONS

The Mark II DiMES PPI has been successfully utilized for detailed characterization of erosion processes at the OSP of L-mode attached and semi-detached plasmas in the DIII-D divertor. Direct comparison between intrinsic emission of CII and CD as a consequence of sputtering processes near the OSP, and those of a localized, controlled artificial injection of CH₄ through a porous cap closely imitating a solid graphite surface have been reported. Integrated emission of CH resulting from the gas puff was found to approximately equal that of intrinsic CD. An inferred contribution of chemical sputtering to C⁺ near the OSP based on the intensity of the CH and CII (426.6 – 426.85 nm) emission cloud from the puff has been found to be ~80% in attached conditions and only ~10% in detached conditions, but is not supported by other C-line emissions, CI (910 nm) and CII (514 and 658 nm), which indicate a C⁰/C⁺ contribution from chemical sputtering of 10%–20%. Resolution of this difference is the focus of ongoing 3D modeling. Effective inverse photon efficiencies D/XB and production efficiencies η for CH have been reported. The intrinsic chemical erosion yield near the OSP has been inferred to be ~2.6% in an attached divertor, and ~1.7% in a semi-detached divertor plasma.

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